



US006918306B1

(12) **United States Patent**  
Cavallaro et al.

(10) **Patent No.:** US 6,918,306 B1  
(45) **Date of Patent:** Jul. 19, 2005

(54) **ADJUSTABLE FLEXURE LOADING APPARATUS FOR TESTING LONG SPAN BEAMS**

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(\*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 55 days.

(21) Appl. No.: **10/657,774**

(22) Filed: **Sep. 8, 2003**

(51) **Int. Cl.**<sup>7</sup> ..... **G01N 3/20**; G01N 3/02

(52) **U.S. Cl.** ..... **73/849**; 73/856

(58) **Field of Search** ..... 73/849, 852, 856, 73/853, 855

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(57) **ABSTRACT**

An adjustable loading apparatus for supporting a long span beam in a flexure test by a load application device is disclosed. The apparatus includes an upper support structure including an elongated support beam, at least one support bracket adjustably mountable along a longitudinal span thereof, and a saddle member selectively pivotally mounted in the at least one upper support bracket for engaging with a specimen under test. The upper support structure is positioned normal to the load application device and a lower support structure is positioned parallel and co-planar to the upper support structure. The lower support structure includes an elongated support beam, at least one spacing member adjustably mounted along a longitudinal span thereof, a lower support bracket adjustably mounted along a longitudinal span of the spacing member, and a saddle selectively pivotally mounted in the lower support bracket for engaging with a specimen under test.

**13 Claims, 2 Drawing Sheets**

